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| Form PTO-1449 | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. 29318US2 | SERIAL NO. 10/809,092 |
| INFORMATION DISCLOSURE CITATION BY APPLICANT <i>(USE SEVERAL SHEETS IF NECESSARY)</i> | | | | APPLICANT: Min-Su Fung, et al. | |
| | | | | FILING DATE: | GROUP ART UNIT: 2529 |

| U.S. PATENT DOCUMENTS | | | | | | | |
|-----------------------|--------------|-----------|-----------------|-------|----------|----------------------------|--|
| Examiner Initial | Document No. | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| VN | A | 4,236,165 | Szedon | | | | |
| VN | B | 4,812,756 | Curtis, et al. | | | | |
| VN | C | 5,216,362 | Verkuil | | | | |
| VN | D | 5,498,974 | Verkuil, et al. | | | | |
| VN | E | 5,767,693 | Verkuil | | | | |
| VN | F | 5,834,941 | Verkuil, et al. | | | | |
| | G | | | | | | |
| | H | | | | | | |

| FOREIGN PATENT DOCUMENTS | | | | | | | |
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| Document No. | Date | Country | Class | Subclass | Translation | | |
| I | | | | | | | |
| J | | | | | | | |

| OTHER REFERENCES <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i> | |
|--------------------------------------------------------------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| VN | K Solid State Technology, Test/Masurement, "Monitoring Electrically Active Contaminants to Assess Oxide Quality", Gregory S. Horner, et al., June 1985, PennWell Publishing Company, 4 Pages. |
| VN | L Semiconductor International, "A New Approach for Measuring Oxide Thickness", Tom G. Miller, July 1995, Cahners Publishing Company, 2 Pages. |
| VN | M "COS Testing Combines Expanded Charge Monitoring Capabilities with Reduced Costs", Michael A. Peters, Semiconductor Fabtech 95, 4 Pages. |
| VN | N Process Monitoring, "Corona Oxide Semiconductor Test", Semiconductor Test Supplement, February/March 1995, Pages S-3 and S-5. |
| VN | O "Quantox™ Non-Contact Oxide Monitoring System", John Bickley, 1995 Keithley Instruments, Inc., No. 1744, 6 Pages. <i>(month unavailable)</i> |

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| Examiner: | Date Considered 12/09/04 |
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***Examiner:** Initial if reference considered, regardless of whether citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.